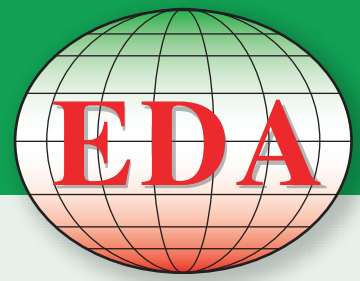
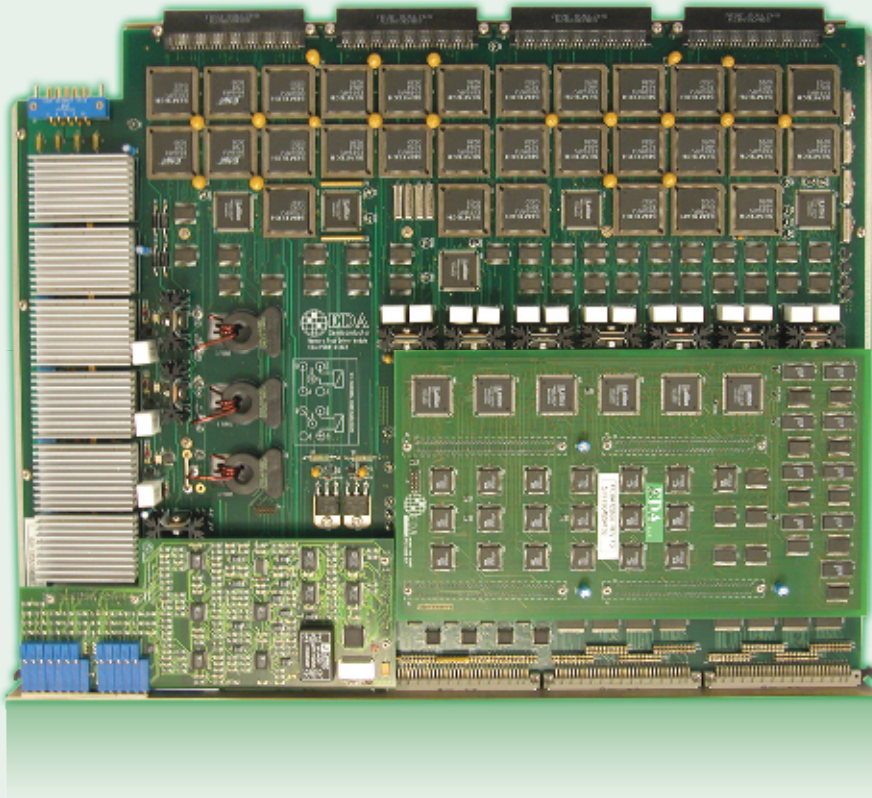


MBTS III Memory Burn-in & Test System



Industries



MAIN FEATURES

- ▶ Burn-in & Test system for all memory devices (DRAM, SRAM, SDRAM, DDR, NOR FLASH, NAND FLASH, EEPROM)
- ▶ Highly flexible modular architecture
- ▶ Based on MPM and MTDM modules
- ▶ Configurable to different BIB Standards
- ▶ Two models available: MBTS III SB and MBTS III HD/H
- ▶ MBTS III SB is compatible with Ando/JEC BiBs
- ▶ Ethernet network architecture
- ▶ User-friendly Software Interface
- ▶ Self-diagnostic & calibration features
- ▶ Integration with BIB Loader/Unloaders

